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» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

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IEEE STD IEEE Standard

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- ☐ **1. VERILAT: verification using logic augmentation and transformations**
 Paul, D.; Chatterjee, M.; Pradhan, D.K.;
[Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on](#)
 Volume 19, Issue 9, Sept. 2000 Page(s):1041 - 1051
 Digital Object Identifier 10.1109/43.863644
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(300 KB) IEEE JNL
[Rights and Permissions](#)
- ☐ **2. PECS: a peak current and power simulator for CMOS combinational circuit:**
 Lam, K.N.; Devadas, S.;
[Circuits and Systems, 1996. ISCAS '96., 'Connecting the World', 1996 IEEE International Symposium on](#)
 Volume 4, 12-15 May 1996 Page(s):488 - 491 vol.4
 Digital Object Identifier 10.1109/ISCAS.1996.542007
[AbstractPlus](#) | Full Text: [PDF](#)(316 KB) IEEE CNF
[Rights and Permissions](#)
- ☐ **3. An efficient perfect algorithm for memory repair problems**
 Hung-Yau Lin; Fu-Min Yeh; Ing-Yi Chen; Sy-Yen Kuo;
[Defect and Fault Tolerance in VLSI Systems, 2004. DFT 2004. Proceedings. 19th International Symposium on](#)
 10-13 Oct. 2004 Page(s):306 - 313
 Digital Object Identifier 10.1109/DFTVS.2004.1347853
[AbstractPlus](#) | Full Text: [PDF](#)(705 KB) IEEE CNF
[Rights and Permissions](#)
- ☐ **4. A Boolean algebra method for computing the terminal reliability in a comm network**
 Fratta, L.; Montanari, U.;
[Circuits and Systems, IEEE Transactions on \[legacy, pre - 1988\]](#)
 Volume 20, Issue 3, May 1973 Page(s):203 - 211
[AbstractPlus](#) | Full Text: [PDF](#)(896 KB) IEEE JNL
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EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	5120	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L2	10722	stat\$6 same circuit	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L3	468	(stat\$6 same circuit) same transform\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L4	35	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and rtl and test	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L5	3	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and (stat\$5 near4 circuit)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L6	49	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and transform\$4 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L7	37	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and rtl and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L8	18	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and rtl and node and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06

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L9	32	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and rtl and port\$3 and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L10	49	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and rtl and port\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L11	64	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and rtl	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L12	34	((statis\$6 same circuit) same transform\$5) and node and portion	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:08
L13	23	((statis\$6 same circuit) same transform\$5)) and ("716"/\$.ccls. or "710"/\$.ccls. or "712"/\$.ccls.) and statis\$6	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L14	23	((statis\$6 same circuit) same transform\$5)) and ("716"/\$.ccls. or "710"/\$.ccls. or "712"/\$.ccls.) and statis\$6 and transform\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L15	121	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and "716"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L16	406	(duplicat\$4 or replicat\$4) with (flip-flop or (flip adj flop) or register) and transform\$4 and node	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06

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L17	2	((statis\$6 same circuit) same transform\$5) and node and portion and (rtl or register adj transfer adj level)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L18	2	((statis\$6 same circuit) same transform\$5) and node and (rtl or register adj transfer adj level)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L19	2	((statis\$6 same circuit) same transform\$5) and node and (rtl or (register adj transfer adj level))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:06
L20	9	((statis\$6 same circuit) same transform\$5) and node and boolean	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:07
L21	15	((statis\$6 same circuit) same transform\$5) and boolean	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:07
L22	14	((statis\$6 same circuit) same transform\$5) and node and portion and circuit and data and gate	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:10
L23	0	((statis\$6 same circuit) same transform\$5) and node and portion and circuit and data and gate).CLM.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:10

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L23	0	((stat\$6 same circuit) same transform\$5) and node and portion and circuit and data and gate).CLM.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/06/10 13:10